



Notice of References Cited

Application/Control No.  
10/664,631

Applicant(s)/Patent Under  
Reexamination  
ERAN ET AL.

Examiner  
TUAN H. NGUYEN

Art Unit  
2618

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0203740	10-2004	Won et al,	455/426.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

FORM PTO-1449 (Colb)		ATTY DOCKET NO. 91366	SERIAL NUMBER 10/764,963
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT		APPLICANT Eran SHPAK	EXAMINER (N/A)
MAY 05 2008		FILING DATE January 26, 2004	GROUP ART UNIT 3679

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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	2004/0203740	10-2004	Won, et al.			
	AB						
	AC						
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	AG						
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	AJ						

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANSLATION
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